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**FUJITSU PATENT APPLICATIONS AND ISSUED PATENTS**

| FJ No.   | JPO Application No. | JPO Filing Date | Registration Date | Title   | Publication No. | Registration No. | Publication Date |
|----------|---------------------|-----------------|-------------------|---|-----------------|------------------|------------------|
| 89P02073 | H 1- 54998          | 19890309        | 19990319          | SEMICONDUCTOR DEVICE  | H 2-236178      | 2900941          | 19900919         |
| 93-07392 | H 5-286658          | 19931116        | 20030411          | CURRENT MIRROR TYPE OSCILLATOR CIRCUIT                                  | H 7-142964      | 3418435          | 02.06.1995       |
| 93-07809 | H 5-329285          | 19931227        | 20030320          | FLASH MEMORY  | H 7-192480      | 3409404          | 28.07.1995       |
| 94-00077 | H 6-115360          | 19940527        | 20030404          | SEMICONDUCTOR DEVICE  | H 7-321207      | 3414496          | 08.12.1995       |
| 94-05461 | H 6-168270          | 19940720        | 20030404          | SEMICONDUCTOR MEMORY  | H 8- 32437      | 3414852          | 02.02.1996       |
| 93-01191 | H 5-152249          | 19930623        | 20040416          | SEMICONDUCTOR STORAGE DEVICE  | H 7- 21792      | 3545010          | 24.01.1995       |
| 93-08115 | H 5-313341          | 19931214        | 2004.07.23        | NON-VOLTAGE SEMICONDUCTOR MEMORY  | H 7-169287      | 3578478          | 04.07.1995       |
| 93-09804 | H 5-310244          | 19931210        | 2004.07.09        | ELECTRICALLY ERASABLE NON-VOLATILE SEMICONDUCTOR MEMORY                 | H 7-169280      | 3573477          | 04.07.1995       |
| 93-12588 | H 6- 48084          | 19940318        | 20040416          | NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND DATA READING METHOD THEREOF | H 7-262787      | 3544222          | 13.10.1995       |
| 93-12603 | H 6- 48116          | 19940318        | 2004.03.19        | SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE                                 | H 7-263507      | 3534815          | 13.10.1995       |
| 93-14364 | H 6-113271          | 19940527        | 2004.04.09        | FLASH MEMORY  | H 7-320492      | 3541427          | 08.12.1995       |
| 94-03231 | H 6-220387          | 19940914        | 2004.09.24        | SEMICONDUCTOR MEMORY DEVICE   | H 8- 87898      | 3599793          | 02.04.1996       |
| 94-05460 | H 7- 30629          | 19950220        | 2004.06.25        | SEMICONDUCTOR MEMORY DEVICE   | H 8-221998      | 3568265          | 30.08.1996       |
| 94-07025 | H 7- 2771           | 19950111        | 2004.04.16        | NONVOLATILE SEMICONDUCTOR STORAGE DEVICE                                | H 8-195090      | 3544731          | 30.07.1996       |
| 94-11161 | H 7-155664          | 19950622        | 2003.08.29        | DATA OUTPUT CIRCUIT AND SEMICONDUCTOR MEMORY DEVICE                     | H 9- 8640       | 3465416          | 10.01.1997       |
| 94-11600 | H 7-190846          | 19950726        | 2004.05.28        | METHOD AND EQUIPMENT FOR TESTING NONVOLATILE MEMORY                     | H 9- 45100      | 3558746          | 14.02.1997       |
| 95-00231 | H 7-173097          | 19950710        | 2004.04.09        | SEMICONDUCTOR MEMORY  | H 9- 27195      | 3541503          | 28.01.1997       |
| 96-04915 | H 9- 66790          | 19970319        |                   | SEMICONDUCTOR DEVICE AND ITS MANUFACTURE                                | H10-261726      |                  | 29.09.1998       |
| 97-00692 | H 9-211663          | 19970806        | 2004.11.05        | MANUFACTURE OF SEMICONDUCTOR DEVICE                                     | H11- 54638      | 3613312          | 26.02.1999       |
| 97-03900 | H10- 66888          | 19980317        |                   | MANUFACTURE OF SEMICONDUCTOR DEVICE                                     | H11-265994      |                  | 28.09.1999       |
| 99-40161 | H11-226913          | 19990810        |                   | MULTI-BIT NON-VOLATILE MEMORY UTILIZING NON-CONDUCTIVE CHARGE TRAP GATE | 2001- 57093     |                  | 27.02.2001       |

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|----------|---------------------------|-----------------------|----------------------|--|--------------------|------------------|---------------------|
| 99-40214 | H11-334916                | 19991125              |                      | NON-VOLATILE<br>SEMICONDUCTOR<br>MEMORY DEVICE AND<br>ITS MANUFACTURING<br>METHOD                                | 2001-156272        |                  | 08.06.2001          |
| 99-40253 | H11-250780                | 19990903              |                      | SEMICONDUCTOR<br>STORAGE DEVICE AND<br>MANUFACTURE<br>THEREOF  | 2001- 77215        |                  | 23.03.2001          |
| 99-40272 | H11-294199                | 19991015              |                      | SEMICONDUCTOR<br>MEMORY AND USAGE<br>METHOD THEREFOR   | 2001-118940        |                  | 27.04.2001          |
| 00-40262 | 2000-159102               | 20000529              |                      | SEMICONDUCTOR<br>TESTER  | 2001-337128        |                  | 07.12.2001          |
| 00-40755 | 2000-245859               | 20000814              |                      | METHOD FOR<br>MANUFACTURING<br>NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY AND THE<br>SAME<br>MANUFACTURED<br>THEREBY | 2001-326288        |                  | 22.11.2001          |
| 00-41159 | 2003-500918               | 20010525              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE   | WO02/09782<br>1    |                  | 20021205            |
| 00-41238 | 2002-177482               | 20020618              |                      | METHOD AND DEVICE<br>FOR READING DUAL<br>BIT MEMORY CELL   | 2003- 68087        |                  | 07.03.2003          |
| 01-40131 | 2003-131767               | 20030509              |                      | METHOD AND CIRCUIT<br>FOR READING TWO<br>BIT TYPE MEMORY<br>CELL, AND<br>SEMICONDUCTOR<br>MEMORY DEVICE          | 2003-331592        |                  | 21.11.2003          |
| 01-40674 | 2001-367052               | 20011130              |                      | SEMICONDUCTOR<br>MEMORY AND ITS<br>DRIVING METHOD  | 2003-173690        |                  | 20.06.2003          |
| 01-41108 | 2002- 72350               | 20020315              |                      | SEMICONDUCTOR<br>DEVICE  | 2003-270302        |                  | 25.09.2003          |
| 01-41547 | 2002-319913               | 20021101              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY   | 2004-158052        |                  | 03.06.2004          |
| 02-40035 | 2002-250932               | 20020829              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE AND<br>DATA WRITING<br>METHOD                                     | 2004-94987         |                  | 25.03.2004          |
| 02-40036 | 2002-234857               | 20020812              |                      | VOLTAGE CONTROL<br>CIRCUIT AND<br>SEMICONDUCTOR<br>MEMORY DEVICE   | 2004-79036         |                  | 11.03.2004          |
| 02-40072 | 2003-122155               | 20030425              |                      | SYSTEM FOR<br>CONTROLLING PRE-<br>CHARGE LEVEL IN<br>MEMORY DEVICE   | 2003-323796        |                  | 14.11.2003          |
| 02-40253 | 2002- 80554               | 20020322              |                      | SEMICONDUCTOR<br>MEMORY DEVICE   | 2003-281896        |                  | 03.10.2003          |
| 02-40254 | 2002-234463               | 20020812              |                      | NONVOLATILE<br>MEMORY HAVING<br>TRAP LAYER   | 2004-79602         |                  | 11.03.2004          |
| 02-40562 | 2002-319914               | 20021101              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE   | 2004-158053        |                  | 03.06.2004          |
| 02-40878 | 2002-313954               | 20021029              |                      | SEMICONDUCTOR<br>INTEGRATED CIRCUIT  | 2004-152341        |                  | 27.05.2004          |
| 02-41001 | 2003- 9355                | 20030117              |                      | NONVOLATILE MULTI-<br>LEVEL<br>SEMICONDUCTOR<br>MEMORY   | 2004-220728        |                  | 05.08.2004          |

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|----------|---------------------------|-----------------------|----------------------|--|--------------------|------------------|---------------------|
| 02-41003 | 2003- 39689               | 20030218              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY   | 2004-253021        |                  | 09.09.2004          |
| 02-41118 | 2003- 17466               | 20030127              |                      | SEMICONDUCTOR<br>STORAGE DEVICE<br>EQUIPPED WITH HIGH<br>SPEED READOUT<br>CIRCUIT  | 2004-227486        |                  | 12.08.2004          |
| 02-41195 | 2002-269838               | 20020917              |                      | OPTICAL RECORDING<br>MEDIUM FOR<br>INSPECTION, METHOD<br>FOR MANUFACTURING<br>OPTICAL RECORDING<br>MEDIUM FOR<br>INSPECTION AND DISK<br>DRIVE INSPECTION<br>METHOD | 2002-269838        |                  | 20.09.2002          |
| 02-41217 | 2002-265065               | 20020911              |                      | MEMORY CIRCUIT<br>HAVING REDUNDANCY<br>CONSTITUTION  | 2004-103143        |                  | 02.04.2004          |
| 02-41218 | 2002-268316               | 20020913              |                      | METHOD FOR<br>DESIGNING<br>SEMICONDUCTOR<br>MEMORY DEVICE, AND<br>SEMICONDUCTOR<br>MEMORY DEVICE   | 2004-111443        |                  | 08.04.2004          |
| 02-41219 | 2002-267097               | 20020912              |                      | SEMICONDUCTOR<br>NONVOLATILE<br>MEMORY WHICH HAS<br>IMPROVED TRACKING<br>CHARACTERISTIC  | 2004-103181        |                  | 02.04.2004          |
| 02-41222 | 2002-268643               | 20020913              |                      | NONVOLATILE<br>MEMORY CIRCUIT AND<br>NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE  | 2004-110883        |                  | 08.04.2004          |
| 02-41532 | 2003- 38636               | 20030217              |                      | STEP-UP CIRCUIT OF<br>SMALL AREA WITH<br>MULTISTAGE<br>STRUCTURE   | 2004-247689        |                  | 02.09.2004          |
| 02-41534 | 2003- 38642               | 20030217              |                      | CHARGE PUMP<br>CIRCUIT WITH<br>REDUCED AMPLITUDE<br>OF STEP-UP VOLTAGE   | 2004-248475        |                  | 02.09.2004          |
| 02-41535 | 2003- 73287               | 20030318              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY AND ITS<br>OPERATION CONTROL<br>METHOD  | 2004-280981        |                  | 07.10.2004          |
| 02-41634 | 2002-370272               | 20021220              |                      | CONTROL METHOD OF<br>NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE,<br>AND NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE   | 2004-199833        |                  | 15.07.2004          |
| 02-41637 | 2002-370273               | 20021220              |                      | METHOD OF<br>CONTROLLING<br>SEMICONDUCTOR<br>DEVICE, AND THE<br>SEMICONDUCTOR<br>DEVICE  | 2004-199600        |                  | 15.07.2004          |
| 02-41643 | 2002-370275               | 20021220              |                      | SEMICONDUCTOR<br>DEVICE,<br>SEMICONDUCTOR<br>STORAGE DEVICE,<br>AND TEST METHOD<br>THEREFOR  | 2004-199834        |                  | 15.07.2004          |
| 02-41644 | 2002-370276               | 20021220              |                      | SEMICONDUCTOR<br>STORAGE DEVICE AND  | 2004-199835        |                  | 15.07.2004          |

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|          |                           |                       |                      | TEST METHOD<br>THEREFOR   |                    |                  |                     |
| 02-41660 | 2002-348485               | 20021129              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE AND<br>SEMICONDUCTOR<br>DEVICE                             | 2004-185670        |                  | 02.07.2004          |
| 02-41661 | 2002-342677               | 20021126              |                      | SEMICONDUCTOR<br>DEVICE AND ITS<br>TESTING METHOD   | 2004-178672        |                  | 24.06.2004          |
| 02-41696 | 2002-371126               | 20021220              |                      | SEMICONDUCTOR<br>MEMORY DEVICE AND<br>ITS CONTROL<br>METHOD   | 2004-206740        |                  | 22.07.2004          |
| 02-41698 | 2002-370277               | 20021220              |                      | CONTROL METHOD OF<br>NONVOLATILE<br>MEMORY, AND<br>NONVOLATILE<br>MEMORY                                  | 2004-199836        |                  | 15.07.2004          |
| 02-41702 | 2003- 76960               | 20030320              |                      | SEMICONDUCTOR<br>MEMORY DEVICE  | 2004-288260        |                  | 14.10.2004          |
| 02-41719 | 2003- 87868               | 20030327              |                      | CHARGING PUMP<br>CIRCUIT  | 2004-297922        |                  | 21.10.2004          |
| 02-41730 | 2002-369554               | 20021220              |                      | SEMICONDUCTOR<br>STORAGE DEVICE AND<br>ITS CONTROL<br>METHOD  | 2004-199825        |                  | 15.07.2004          |
| 03-40053 | PCT                       | 20030428              |                      |   |                    |                  |                     |
| 03-40222 | 2003-136269               | 20030514              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE AND<br>METHOD FOR<br>DETERMINING DATA                      | 2004-047050        |                  | 12.02.2004          |
| 99-40337 | H11-293027                | 19991014              |                      | NON-VOLATILE<br>MEMORY CIRCUIT<br>RECORDING MULTI-BIT<br>INFORMATION                                      | 2001-118390        |                  | 27.04.2001          |
| 00-40018 | 2002-518468               | 20000803              |                      |   | WO02/01319<br>9    |                  | 14.02.2002          |
| 00-40619 | 2002-551860               | 20001221              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY AND<br>METHOD OF ERASURE   | WO2002/050<br>843  |                  | 20020627            |
| 00-40996 | 2001-123180               | 20010420              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY  | 2002-319287        |                  | 31.10.2002          |
| 01-40129 | 2003-114392               | 20030418              |                      | METHOD AND SYSTEM<br>FOR PROGRAMMING<br>THRESHOLD VOLTAGE<br>LEVEL AND<br>SEMICONDUCTOR<br>STORAGE DEVICE | 2003-323793        |                  | 14.11.2003          |
| 01-40756 | 2001-252400               | 20010823              |                      | MEMORY<br>CONTROLLER FOR<br>MULTI-VALUE CELL<br>MEMORY  | 2003- 67260        |                  | 07.03.2003          |
| 01-41067 | 2003- 51449               | 20030227              |                      | SYSTEM FOR SETTING<br>MEMORY VOLTAGE<br>THRESHOLD   | 2003-263895        |                  | 19.09.2003          |
| 01-41415 | 2002-114145               | 20020417              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY AND<br>METHOD OF<br>MANUFACTURING THE<br>SAME                      | 2003-309192        |                  | 31.10.2003          |
| 01-41516 | 2002- 53994               | 20020228              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY DEVICE   | 2003-257188        |                  | 12.09.2003          |

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| 02-40420 | 2003-159556               | 20030604              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY  | 2004-273093                      |                  | 30.09.2004          |
| 02-41214 | 2002-268606               | 20020913              |                      | SEMICONDUCTOR<br>MEMORY   | 2004-110881                      |                  | 08.04.2004          |
| 02-41221 | 2002-268317               | 20020913              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE  | 2004-110872                      |                  | 08.04.2004          |
| 98-40297 | H11-209787                | 19990723              |                      | NON-VOLATILE<br>MEMORY ENABLING<br>ENCRPTION OF<br>COMMAND  | 2001- 35171                      |                  | 09.02.2001          |
| 99-40506 | 2001-560823               | 20000216              |                      | NONVOLATILE<br>MEMORY   | 2001-<br>861503 (WO<br>1/061503) |                  | 20010823            |
| 00-40048 | 2002-505627               | 20000629              |                      | SEMICONDUCTOR<br>MEMORY DEVICE  | WO02/00157<br>4                  |                  | 20020103            |
| 01-40842 | 2002- 12985               | 20020122              |                      | SEMICONDUCTOR<br>NONVOLATILE<br>MEMORY WITH<br>FRAUDULENT<br>READING<br>PREVENTING<br>FEATURE   | 2003-216499                      |                  | 31.07.2003          |
| 01-40865 | 2002- 45116               | 20020221              |                      | ERROR<br>DETECTING/CORRECTI<br>NG METHOD FOR<br>MULTI-LEVEL<br>SEMICONDUCTOR<br>MEMORY, AND MULTI-<br>LEVEL<br>SEMICONDUCTOR<br>MEMORY HAVING<br>ERROR<br>DETECTING/CORRECTI<br>NG FUNCTION | 2003- 36693                      |                  | 07.02.2003          |
| 01-41056 | 2001-322813               | 20011019              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY AND<br>CONTROL METHOD<br>THEREFOR  | 2003-132688                      |                  | 09.05.2003          |
| 01-41288 | 2002-120548               | 20020423              |                      | LOW TEMPERATURE<br>TEST APPARATUS FOR<br>SEMICONDUCTOR<br>DEVICE USING<br>ELECTRONIC<br>COOLING ELEMENT   | 2003-315406                      |                  | 06.11.2003          |
| 01-41306 | 2002- 4150                | 20020111              |                      | MEMORY DEVICE   | 2002-328836                      |                  | 15.11.2002          |
| 02-40528 | 2002-231825               | 20020808              |                      | METHOD FOR<br>CONTROLLING<br>SEMICONDUCTOR<br>MEMORY DEVICE AND<br>SEMICONDUCTOR<br>MEMORY DEVICE   | 2004-71105                       |                  | 04.03.2004          |
| 02-41215 | 2002-268315               | 20020913              |                      | NONVOLATILE<br>SEMICONDUCTOR<br>STORAGE DEVICE  | 2004-110871                      |                  | 08.04.2004          |
| 02-41410 | PCT/JP2003/<br>001971     | 20030224              |                      | VOLTAGE SENSING<br>CIRCUIT,<br>SEMICONDUCTOR<br>DEVICE, METHOD FOR<br>CONTROLLING<br>VOLTAGE SENSING<br>CIRCUIT   | WO20040752<br>02                 |                  | 20040902            |

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| 02-41434 | PCT/JP2003/001739   | 20030218  |                   | SEMICONDUCTOR5 STORAGE DEVICE AND SEMICONDUCTOR STORAGE DEVICE READ OUT METHOD      | WO2004075199    |                  | 20040902         |
| 02-41531 | 2004-568757         | 20030227  |                   |   |                 |                  |                  |
| 02-41615 | 2004-568776         | 20030228  |                   |   |                 |                  |                  |
| 02-41642 | 2002-370274         | 20021220  |                   | SEMICONDUCTOR DEVICE AND ITS TESTING METHOD   | 2004-198367     |                  | 15.07.2004       |
| 02-41651 | 2005-500549         | 20030605  |                   |   |                 |                  |                  |
| 02-41655 | 2005-500550         | 20030605  |                   |   |                 |                  |                  |
| 02-41656 | 2004-571303         | 20030430  |                   |   |                 |                  |                  |
| 02-41690 | 2004-569330         | 20030311  |                   |   |                 |                  |                  |
| 02-41701 | 2002-370278         | 20021220  |                   | NONVOLATILE MEMORY AND WRITING METHOD THEREFOR                                      | 2004-199837     |                  | 15.07.2004       |
| 02-41729 | 2002-377039         | 20021226  |                   | SEMICONDUCTOR MEMORY AND CONTROL METHOD FOR SEMICONDUCTOR MEMORY                    | 2004-206832     |                  | 22.07.2004       |
| 02-41828 | 2002-374366         | 20021225  |                   | STORAGE METHOD AND STORAGE DEVICE FOR NONVOLATILE MEMORY                            | 2004-206381     |                  | 22.07.2004       |
| 03-40052 | 2003- 50264         | 20030227  |                   | SEMICONDUCTOR MEMORY DEVICE   | 2004-259385     |                  | 16.09.2004       |
| 03-40067 | PCT                 | 20030424  |                   |   |                 |                  |                  |
| 03-40184 | PCT                 | 20030417  |                   |   |                 |                  |                  |
| 03-40729 | 2005-500563         | 20030605  |                   |   |                 |                  |                  |
| 91P08819 | 1991-240040(H03)    | 19910919  | 26.09.2003        | SEMICONDUCTOR MEMORY  | H05-81887       | 3476479          | 02.04.1993       |
| 99-40900 | JP2000/004801       | 20000717  |                   | SYSTEM FOR UTILIZING DYNAMIC REFERENCE BY TWO-BIT CELL MEMORY                       | WO2002007215    |                  |                  |
| 01-41290 | 2003-274071         | 20030714  |                   | SYSTEM FOR UTILIZING DYNAMIC REFERENCE BY TWO-BIT CELL MEMORY                       | 2004-039234     |                  | 05.02.2004       |
| 02-41032 | 2002-267680         | 20020913  |                   | SEMICONDUCTOR MEMORY FOR NORMALLY PERFORMING REPLACEMENT WITH REDUNDANCY CELL ARRAY | 2004-110861     |                  | 08.04.2004       |
| 02-40906 | 2003-380841         | Outsource d 14.08.05 20031111 Priority Date 20030606) |                   | NONVOLATILE SEMICONDUCTOR STORAGE DEVICE  | 2004-362729     |                  | 24.12.2004       |

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| 00-40183 | 2000-141072         | 20000515        |                   | NON-VOLATILE SEMICONDUCTOR MEMORY, AND DATA HOLDING METHOD FOR NON-VOLATILE SEMICONDUCTOR MEMORY | 2001-325793     |                  | 22.11.2001       |
| 99-40134 | H11-300401          | 19991022        | 2003.05.16        | NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME                     | 2001-118943     | 3430084          |                  |
| 91P10042 | H03-279308          | 19911025        |                   | NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND MANUFACTURE THEREOF                                  | H05-121702      |                  |                  |
| 99-40225 | H11-266074          | 19990920        |                   | SEMICONDUCTOR INTEGRATED-CIRCUIT DEVICE AND MANUFACTURING METHOD THEREOF                         | 2001-094076     |                  |                  |
| 98-02045 | H10-345307          | 19981204        |                   | MANUFACTURE OF SEMICONDUCTOR DEVICE  | 2000-174235     |                  |                  |
| 99-40258 | H11-266075          | 19990920        | 2004.01.16        | NONVOLTAILE SEMICONDUCTOR STORAGE, WRITING METHOD AND READING METHOD THEREFOR                    | 2001-093995     | 3513056          |                  |
| 00-41250 | 2001-076585         | 20010316        |                   | SEMICONDUCTOR DEVICE AND ITS FABRICATING METHOD  | 2002-280464     |                  |                  |
| 01-40212 | 2001-094582         | 20010329        |                   | SEMICONDUCTOR MEMORY AND ITS DRIVING METHOD  | 2002-299473     |                  |                  |
| 97-01109 | H09-184773          | 19970710        |                   | NON-VOLATILE SEMICONDUCTOR DEVICE AND MANUFACTURE THEREOF  | H11-031798      |                  |                  |
| 97-05686 | H10-066898          | 19980317        |                   | SEMICONDUCTOR DEVICE AND ITS MANUFACTURE   | H11-265947      |                  |                  |
| 97-07264 | H10-128682          | 19980512        |                   | MANUFACTURE OF SEMICONDUCTOR DEVICE  | H11-330274      |                  |                  |
| 02-41423 | 2003-030977         | 20030207        |                   | NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND ITS MANUFACTURING METHOD                             | 2004-241698     |                  |                  |
| 91P10155 | H03-277488          | 19911024        | 2003.06.27        | TEST METHOD FOR SEMICONDUCTOR DEVICE   | 1993120900      | 3444902          |                  |
| 98-01577 | H10-308082          | 19981029        |                   | MANUFACTURE OF SEMICONDUCTOR STORAGE DEVICE  | 2000-133727     |                  |                  |
| 98-02046 | H10-349028          | 19981208        |                   | SEMICONDUCTOR STORAGE DEVICE AND MANUFACTURE THEREOF   | 2000-174237     |                  |                  |
| 00-40023 | 2000-209230         | 20000711        |                   | SEMICONDUCTOR STORAGE DEVICE AND ITS MANUFACTURING METHOD  | 2002-026155     |                  |                  |

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| 00-40405 | 2000-276398         | 20000912        |                   | SEMICONDUCTOR STORAGE DEVICE AND ITS CONTROL METHOD  | 2002-093925     |                  |                  |
| 94-03318 | H06-223270          | 19940919        |                   | FLASH MEMORY AND MANUFACTURE THEREOF   | H08-088287      |                  |                  |
| 02-40764 | 2002-266995         | 20020912        |                   | SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF  | 2004-104009     |                  |                  |
| 02-50911 | 2002-230062         | 20020807        |                   | SEMICONDUCTOR STORAGE DEVICE AND ITS MANUFACTURING METHOD                                    | 2004-071877     |                  |                  |
| 02-41448 | 2003-027514         | 20030204        |                   | SEMICONDUCTOR STORAGE DEVICE AND MANUFACTURING METHOD THEREOF                                | 2004-241503     |                  |                  |
| 02-41913 | 2003-104841         | 20030409        |                   | MANUFACTURING METHOD OF SEMICONDUCTOR STORAGE DEVICE   | 2004-311803     |                  |                  |
| 02-41452 | 2003-060360         | 20030306        |                   | MANUFACTURING METHOD OF SEMICONDUCTOR STORAGE DEVICE   | 2004-273643     |                  |                  |
| 01-40603 | 2001-260702         | 20010830        |                   | STATIC RANDOM ACCESS MEMORY WITH NON-VOLATILE DATA HOLDING FUNCTION AND ITS OPERATING METHOD | 2003-068982     |                  |                  |
| 02-40033 | 2002-135688         | 20020510        |                   | NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME                | 2003-332469     |                  |                  |
| 00-41147 | 2000-351444         | 20001117        |                   | NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND MANUFACTURING METHOD THEREOF                    | 2002-158298     |                  |                  |
| 00-41153 | 2001-031320         | 20010207        |                   | SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE SAME                                    | 2002-237540     |                  |                  |
| 97-7547  | 1997-350393 (H09)   | 19971219        | 2003.12.12        | MANUFACTURE OF SEMICONDUCTOR DEVICE  | 1999186261      | 3500564          |                  |
| 90P10187 | 1990-279832 (H02)   | 19901018        | 1997.04.25        | MANUFACTURE OF SEMICONDUCTOR DEVICE  | 1992154124      | 2639202          |                  |
| 96-07070 | H08-318130          | 19961128        | 2003.06.20        | MANUFACTURE OF SEMICONDUCTOR DEVICE  | H10-163456      | 3442596          |                  |
| 02-41600 | 2002-354049         | 20021205        | -                 | NONVOLATILE SEMICONDUCTOR MEMORY   | 2004-158810     | -                |                  |
| 91P07591 | H03-201033          | 19910812        | 1997.11.21        | MANUFACTURE OF SEMICODUCTOR DEVICE   | H05-048046      | 2720645          |                  |
| 02-40107 | 2002-146184         | 20020521        | -                 | NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME                | 2003-338566     | -                |                  |



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|----------|---------------------------|-----------------------|----------------------|---|--------------------|------------------|---------------------|
| 02-40193 | 2002-255919               | 20020830              | -                    | METHOD FOR<br>MANUFACTURING<br>MEMORY INTEGRATED<br>CIRCUIT DEVICE                          | 2004-095904        | -                | 2005.08.25          |
| 02-41716 | 2003-132041               | 20030509              | -                    | NONVOLATILE<br>SEMICONDUCTOR<br>MEMORY DEVICE AND<br>METHOD OF<br>MANUFACTURING THE<br>SAME | 2004-056095        | -                |                     |
| 05-80085 | 2005- 96274               | 20050329              |                      | SEMICONDUCTOR<br>DEVICE   | 2005-229128        |                  |                     |